Phosphite Doping of ALD SiO₂ Membranes Significantly Enhances Proton Conductivity for PEM Water Electrolysis

Figure 1: H⁺ Conductivity of ALD SiO₂ (blue, circle) and ~0.5% PO₄⁻³ doped SiO₂ (orange, square) on a log scale with respect to film deposition temperature. The measured H+ conductivity for a spin coated Nafion ionomer thin film, thickness of 212nm, is shown by the purple dashed line.



References:

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